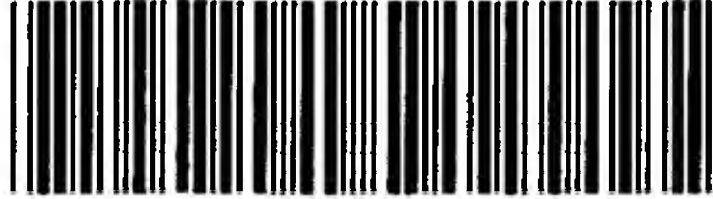


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/560,989	NONAKA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Deborah Yee	1793	

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Class	Subclass	Date	Examiner
148	330-331 330,533	1/8/2008	/DY/
420	120-121	↓	↓
420	129		
428	659		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
west and inventorship search	1/8/2008	/DY/